	 	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	·
10/706,987	TEI ET AL.	
Examiner	Art Unit	
Helen L. Pezzuto	1713	

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	SEAR	CHED	
Class	Subclass	Date	Examiner
526	333		
	336	3/17/2006	HP

INT	ERFERENC	E SEARCH	CHED	
Class	Subclass	Date	Examiner	

SEARCH (INCLUDING SEAR)
	DATE	EXMR
STIC STN search	2/15/2006	HP
West, Inventors search	3/17/2006	НР
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